Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/691,254	GRUMBINE ET AL.	
Examiner	Art Unit	
Kin-Chan Chen	1765	

	SEAR	CHED	
Class	Subclass	Date	Examiner
438	689	10/21/2005	ксс
438	692		
25-2	79.1		
25-2	79.5		
216	89	10/21/05	Kcc

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East Keyword scarch USPAT, USPG-pub. Epo, Jpo, Derwent ZBM-TDB, Inventor scarch	10/21/2005	ксс	
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